

P-Channel MOSFET MEM2309S

Description:

MEM2309SGSeries P-channel enhancement mode field-effect transistor ,produced with high cell density DMOS trench technology, which is especially used to minimize on-state resistance.

This device particularly suits low voltage applications, and low power dissipation.

Feature:

I -30V/-6A

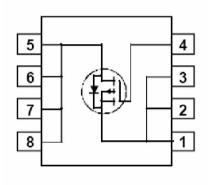
 $R_{DS(ON)} = 53m$ @ $V_{GS} = -10V, I_D = -6A$

 $R_{DS(ON)} = 68m$ @ $V_{GS} = -4.5V$, $I_D = -4A$

- I High Density Cell Design For Ultra Low On-Resistance
- I Surface mount package:SOP8



Pin Configuration:



Typical Application:

- I Power management
- I Load switch
- I Battery protection

Absolute Maximum Ratings:

| Parameter | | Symbol | Ratings | Unit |
|-------------------------------------|--------------------|------------------|---------|------|
| Drain-Source Voltage | | V_{DSS} | -30V | V |
| Gate-Source Voltage | | V_{GSS} | ±20 | V |
| Drain Current | T _A =25 | - I _D | -6 | А |
| | T _A =70 | | -3.2 | A |
| Pulsed Drain Current ^{1,2} | | I _{DM} | -30 | А |
| Total Power Dissipation | T _A =25 | Pd | 2 | W |
| | T _A =70 | | 0.8 | VV |
| Operating Temperature Range | | T_{Opr} | 150 | |
| Storage Temperature Range | | T _{stg} | -65/150 | |



Thermal Characteristics:

| Parameter | Symbol | Ratings | Unit |
|--|--------|---------|------|
| Thermal Resistance, Junction-to-Ambient ³ | R JA | 50 | W |

Electrical Characteristics:

MEM2309SG

| WIEWI23093G | | | | | 1 | | | | |
|--------------------------------------|----------------------|---|------|------|------|------|--|--|--|
| Parameter | Symbol | Test Condition | Min | Туре | Max | Unit | | | |
| Static Characteristics | | | | | | | | | |
| Drain-Source Breakdown Voltage | $V_{(BR)DSS}$ | V_{GS} =0V, I_D =-250uA | -30 | -34 | | V | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS},$ I_{D} =-250uA | -1.1 | -1.3 | -2 | V | | | |
| Cata Bady Laakaga | I _{GSS} | V _{DS} =0V , V _{GS} =20V | | 5 | 30 | nA | | | |
| Gate-Body Leakage | | V_{DS} =0V , V_{GS} =-20V | | -5 | -30 | nA | | | |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} =-24V V _{GS} =0V | | -6 | -300 | nA | | | |
| Static Drain-Source | R _{DS(ON)1} | V _{GS} =-10V,I _D =-6A | 33 | 53 | 65 | m | | | |
| On-Resistance | R _{DS(ON)2} | V_{GS} =-4.5 V , I_{D} =-4 A | 50 | 68 | 80 | m | | | |
| Forward Transconductance | g FS | $V_{DS} = -5 \text{ V},$ $I_{D} = -5.3 \text{ A}$ | | 10 | | S | | | |
| Drain-Source Diode Forward Current | Is | | | | -2.1 | Α | | | |
| Source-drain (diode forward) voltage | V_{SD} | V _{GS} =0V,I _D =-1A | | -0.8 | -1.2 | V | | | |
| | ynamic C | haracteristics | | | | | | | |
| Input Capacitance | Ciss | $V_{DS} = -15V$, | | 530 | | | | | |
| Output Capacitance | Coss | $V_{GS} = 0 V$, | | 140 | | рF | | | |
| Reverse Transfer Capacitance | Crss | f = 1 MHz | | 70 | | | | | |
| Switching Characteristics | | | | | | | | | |
| Turn-On Delay Time | td(on) | $V_{DD} = -15 \text{ V},$ | | 8 | 15 | | | | |
| Rise Time | tr | I _D =-1 A, | | 15 | 25 | no | | | |
| Turn-Off Delay Time | td(off) | $V_{GEN} = -10 \text{ V},$ | - | 15 | 25 | ns | | | |
| Fall-Time | tf | Rg = 6 | | 10 | 15 | | | | |
| Total Gate Charge | Qg | $V_{DS} = -15 V$, | | 10 | 15 | | | | |
| Gate-Source Charge | Qgs | $V_{GS} = -10 \text{ V},$ | | 2.2 | | nc | | | |
| Gate-Drain Charge | Qgd | $I_D = -4A$ | | 2.0 | | | | | |

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^{1、}Repetitive rating, pulse width limited by junction temperature.

^{2、}Pulse test; pulse width 300 us, duty cycle 2%.

^{3、}Surface Mounted on FR4 Board, t 10 sec.



Typical Performance Characteristics:

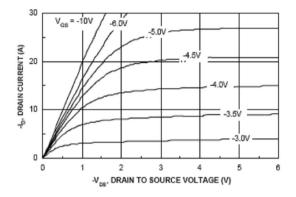


Figure 1. On-Region Characteristics.

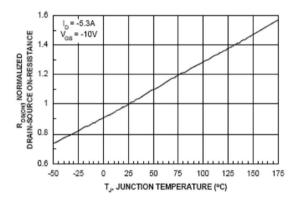


Figure 3. On-Resistance Variation with Temperature.

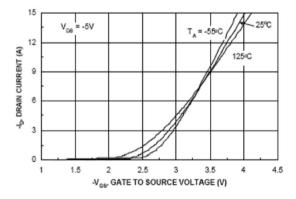


Figure 5. Transfer Characteristics.

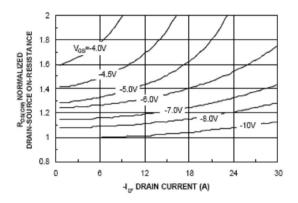


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

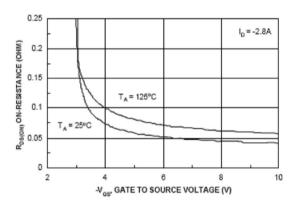


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

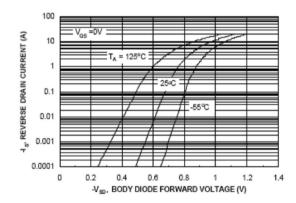
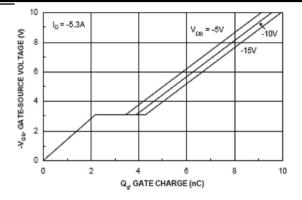


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.





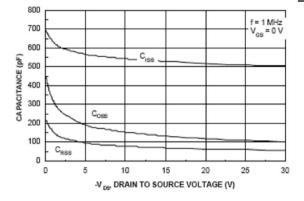


Figure 7. Gate Charge Characteristics.

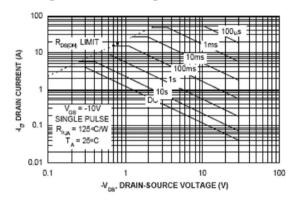


Figure 8. Capacitance Characteristics.

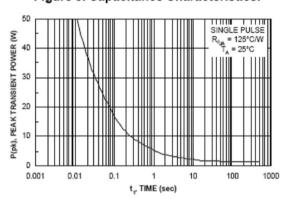


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

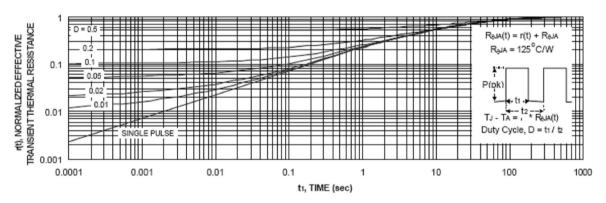


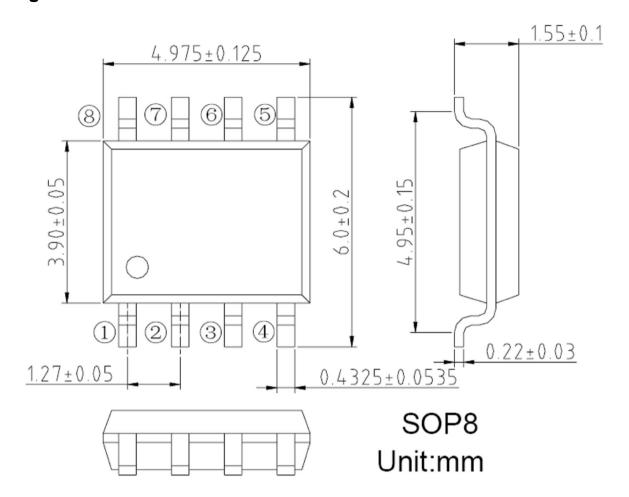
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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